

Aufstellung über eigene Arbeiten und Veröffentlichungen:

Diplomarbeit

Conrad R. Wolf: *Interferometrische Messung von Schwingungen und Drifts an Rasterkraftmikroskopen*, Fachhochschule Ulm (2004).

Dissertation

Conrad R. Wolf: *Contacting single quantum dots with nano-electrodes*, Universität Ulm (2010).

Vorträge

Conrad R. Wolf, Daniel Gerster, Klaus Thonke und Rolf Sauer: *Fabrication of nano-electrodes by means of controlled electrochemical deposition of gold*, DPG Frühjahrstagung 2008, Berlin.

Conrad R. Wolf, Daniel Gerster, Klaus Thonke und Rolf Sauer: *Fabrication of nano-electrodes by means of controlled electrochemical deposition of gold*, Workshop Metal Deposition for Emerging Nanoelectronic Applications, 30.10.2007, Schloß Reisensburg, Günzburg.

Conrad R. Wolf, Klaus Thonke und Rolf Sauer: *Fabrication of silicon quantum dot single-electron transistors by a combination of self-assembly and self-alignment techniques*, E-MRS Spring Meeting 2007, Strasbourg (France).

Conrad R. Wolf, Klaus Thonke und Rolf Sauer: *SOI-based single-electron transistors fabricated by a combination of self-assembly and self-alignment techniques*, DPG Frühjahrstagung 2007, Regensburg.

Poster

Conrad R. Wolf, Klaus Thonke und Rolf Sauer: *Fabrication and characterization of self-assembled and self-aligned SOI-based single-electron transistors*, Trends in Nanoscience 2007, Kloster Irsee.

Conrad R. Wolf, Andreas Ladenburger, Rainer Enchelmaier, Klaus Thonke und Rolf Sauer: *SOI-based silicon quantum dots contacted by self-aligned nano-electrodes*, MRS Fall Meeting 2006, Boston (USA).

Publikationen

Conrad R. Wolf, Klaus Thonke und Rolf Sauer: *Single-electron transistors based on self-assembled silicon-on-insulator quantum dots*. Appl. Phys. Lett. 96 (14), 142108 (2010).

Conrad R. Wolf, Andreas Ladenburger, Rainer Enchelmaier, Klaus Thonke und Rolf Sauer: *SOI-based silicon quantum dots contacted by self-aligned nano-electrodes*, MRS Proc. 958, L10-21 (2007).

David O. S. Melville, Richard J. Blaikie und Conrad R. Wolf: *Submicron imaging with a planar silver lens*, Appl. Phys. Lett. 84, 4403–4405 (2004).